Government eProcurement System

Government eProcurement System

Tender Details

Date : 17-Aug-2022 11:28 AM

Print

Basic Details			
Organisation Chain	Council of Scientific and Industrial Research||CSIO-Chandigarh - CSIR||Purchase-CSIO - CSIR		
Tender Reference Number	CSIO-3-14-2022		
Tender ID	2022_CSIR_125856_1		
Tender Type	Open Tender	**Form of contract**	EOI
Tender Category	Goods	**No. of Covers**	1
General Technical Evaluation Allowed	No	**ItemWise Technical Evaluation Allowed**	No
Payment Mode	Not Applicable	**Is Multi Currency Allowed For BOQ**	No
Is Multi Currency Allowed For Fee	No	**Allow Two Stage Bidding**	No

Cover Details, No. Of Covers - 1

Cover No	Cover	Document Type	Description
1	Fee/PreQual/Technical/Finance	.pdf	Expression of Interest for Variable Angle Spectroscopic Ellipsometer details attached

Tender Fee Details, [Total Fee in ₹ * - 0.00]

Tender Fee in ₹	0.00		
Fee Payable To	Nil	**Fee Payable At**	Nil
Tender Fee Exemption Allowed	No		

EMD Fee Details

EMD Amount in ₹	0.00	**EMD through BG/ST or EMD Exemption Allowed**	No
EMD Fee Type	fixed	**EMD Percentage**	NA
EMD Payable To	Nil	**EMD Payable At**	Nil

Click to view modification history

Work /Item(s)

Title	EOI for Ellipsometer 3(14)2022				
Work Description	Expression of Interest for Variable Angle Spectroscopic Ellipsometer details attached				
Pre Qualification Details	Please refer Tender documents.				
Independent External Monitor/Remarks	NA				
Show Tender Value in Public Domain	No				
Tender Value in ₹	0.00	**Product Category**	Laboratory and scientific equipment	**Sub category**	NA
Contract Type	Tender	**Bid Validity(Days)**	90	**Period Of Work (Days)**	45
Location	CSIR-CSIO Sector 30 Chandigarh	**Pincode**	160030	**Pre Bid Meeting Place**	NA
Pre Bid Meeting Address	NA	**Pre Bid Meeting Date**	NA	**Bid Opening Place**	Online MS Link (Line in document)

Should Allow NDA Tender	No	**Allow Preferential Bidder**	No

Critical Dates

Publish Date	17-Aug-2022 11:30 AM	**Bid Opening Date**	01-Sep-2022 03:30 PM
Document Download / Sale Start Date	17-Aug-2022 11:30 AM	**Document Download / Sale End Date**	31-Aug-2022 03:00 PM
Clarification Start Date	17-Aug-2022 11:30 AM	**Clarification End Date**	29-Aug-2022 03:00 PM
Bid Submission Start Date	17-Aug-2022 11:30 AM	**Bid Submission End Date**	31-Aug-2022 03:00 PM

Tender Documents

NIT Document

S.No	Document Name	Description	Document Size (in KB)
1	Tendernotice_1.pdf	Expression of Interest for Variable Angle Spectroscopic Ellipsometer details attached	185.91

Work Item Documents

S.No	Document Type	Document Name	Description	Document Size (in KB)
1	Tender Documents	Ellipsometer.pdf	Expression of Interest for Variable Angle Spectroscopic Ellipsometer details attached	171.63

Auto Extension Corrigendum Properties for Tender

Iteration	No. of bids required for bid opening a tender	Tender gets extended to No. of days
1.	2	7

Bid Openers List

S.No	Bid Opener Login Id	Bid Opener Name	Certificate Name
1.	ramesh.eproc@csir.res.in	Ramesh Kumar	RAMESH KUMAR
2.	sunder.eproc@csir.res.in	Sunder Lal	SUNDER LAL
3.	jayantrao.eproc@csir.res.in	Jayant Mohan Rao	JAYANT MOHAN RAO
4.	anilyadav.eproc@csir.res.in	Anil Kumar Yadav	ANIL KUMAR YADAV

GeMARPTS Details

GeMARPTS ID	LDULKFU948VM
Description	variable angle Spectroscopic Ellipsometer
Report Initiated On	17-Aug-2022
Valid Until	16-Sep-2022

Tender Properties

Auto Tendering Process allowed	No	**Show Technical bid status**	Yes
Show Finance bid status	Yes	**Show Bids Details**	Yes
BoQ Comparative Chart model	NIL	BoQ Compartive chart decimal places	2
BoQ Comparative Chart Rank Type	NIL	Form Based BoQ	No

Tender Inviting Authority

Name	Controller ofStores Purchase
Address	The Director CSIR-CSIO Sector 30 Chandigarh

Tender Creator Details

Created By	Ramesh Kumar
Designation	Assistant
Created Date	17-Aug-2022 11:19 AM

Tentative Technical Specifications

S/No.	Parameter	Specifications
1.	Wavelength Range	from (200 ± 10) nm to 2500 nm or higher
2.	Make and Model	The Make and Model of the offered equipment must be clearly mentioned along with hardware and software extensions to meet the specifications
3.	Spectral Resolution (Wavelength spacing)	≤ 1 nm in UV/Vis ≤ 6 nm in NIR
4.	Standard Beam Diameter	< 5 mm
5.	Accuracy	Straight Through Accuracy of 10 second measurement of empty beam (air) is required for 95% of all wavelength as below: For Wavelength range (200 ± 10) nm to 1000 nm: Psi 45° ± 0.05° or better, Delta 0° ± 0.1° or better For Wavelength range 1000 – 2500 nm: Psi 45° ± 0.1° or better, Delta 0° ± 0.2° or better
6.	Repeatability/Precision	Standard Deviation of Thirty consecutive measurements of nominally 25nm thick SiO2/Si standard must be ≤ 0.02 nm *(CSIO may provide a sample while inviting bids and all the bidders will be required to submit a measurement report conforming to this repeatability requirement using the same model and configuration of the equipment as offered to CSIO.)*
7.	Lamp Source	The vendor must clearly specify suitable illumination source covering the above wavelength range with a lifetime of more than 1000 hours of continuous operation
8.	Detector	The vendor must specify appropriate detectors for UV-Vis and NIR Wavelengths along with necessary cooling arrangements as required
9.	Mueller Matrix Elements	The system must be capable of measuring 16 elements of Mueller Matrix; the vendor must quote the required hardware and/or software extension to achieve this.
10.	Polarizer/Analyzer/ Compensator	The system must have high grade MgF_2Rochon polarizers and analyzers along with appropriate compensators to meet the requirement in S/no. 5 The polarizer , compensator and analyzer must be motorized and computer controlled.
11.	Automatic Goniometer	The system must have automatic and computer

		controlled goniometer for angle adjustment in the range 45 – 90° or better with an accuracy of ±0.02° or better, repeatability/precision of ≤0.005° or better and step size of 0.04°or better.
12.	Sample Stage	The system must be able to hold optical substrates/wafers upto 200 mm in diameter along with suitable vacuum chuck. It should also be capable of holding samples of various shapes and sizes.
13.	Sample Viewing	CCD camera
14.	Sample Alignment and Adjustment	The system must have samplealignment with automated tip/tilt and z-height adjustment or through microscope-collimator set-up to avail optimal reflected intensity from the sample during measurement.
15.	Focusing Probe	Necessary optics should be provided to allow measurement on small or patterned areas. The system must have suitable Focusing probe to generate a beam size of ≤200 µm
16.	Measurable film parameters	Refractive index, extinction coefficient, absorption coefficient and film thickness
17.	Fitting & Control Software	– The system must be supplied with appropriate control and fitting software. The fitting software must support easy calibration, automatic data acquisition, automatic mapping and fitting, provision to import/export data. The fitting software must contain an exhaustive library of group IV, III-V compound semiconductors, dielectric materials (at least 200 material types in total or better) and several dispersion models (at least 20 or better) used for fitting n and k values and thickness extraction for different materials. – The software must come with at least 2 perpetual seat licenses and software manual explaining detailed working and tuning of the software.
18.	Electrical Connections	Compliance to power supply of 230V +/- 10%, 1 Phase, 50Hz +/- 5% Or 415V +/- 10%/3 Phase, 50 Hz +/- 5%
19.	PC	The system must come with a compatible control PC with thefollowing accessory – Operating System: Windows 10/11

		Professional – MS Office 2019 or latest (activated) – with preinstalled driver and fitting software for SE measurement and analysis – Display Screen: 24 inch or Higher Size monitor – With internal/external CD/DVD writer: 1
20.	Workbench/Racks etc.	The quote must include an integrated appropriate platform/workbench (if any) to house/support all thecontrol electronics and the vendor should also provide complete set of tools required for servicing and maintaining the system.
21.	Calibration Standard	The vendor shall also provide relevant standard calibration samples of SiO_2 on Si (2 Nos. – One each of 25 nm and 100 nm thick SiO_2) and any other calibration samples that would be essential
22.	Spares	The vendor shall provide 1 No. of spare lamp to cover the offered wavelength range and any other relevant spares.
23.	Warranty	At least 2 Years Warranty after satisfactory installation and the vendor must quote Non-comprehensive AMC Prices for a 5 year period after the expiry of 2 Year Warranty
24.	Installation/Training	The firm must provide installation and training (for minimum 3 days) at CSIO Chandigarh
25.	Documentation	1 set of technical documentation to be offered along with the system (Hard copy and Soft Copy)
26.	Essential requirements	Vendor must have supplied similar instrument in India and must provide contact details/customer list of Indian R&D laboratories/Industries where such instrument have been supplied in the last ten years.

Date of EOI Meeting: 30.08.2022 (Tuesday)

Time: 10:00 AM
Mode: Online/Virtual Mode through MS Teams
Meeting LInk:
https://teams.microsoft.com/l/meetup-join/19%3ameeting_MjQwMGFlZjItZWEyNi00YTg2LWJjMjYtYzBkMzY2YzMwZjY3%40thread.v2/0?context=%7b%22Tid%22%3a%22b867f20e-8a9c-4603-b5ab-39c3840dfb64%22%2c%22Oid%22%3a%22cb96dee7-e449-464a-b6ac-a13c5a179694%22%7d